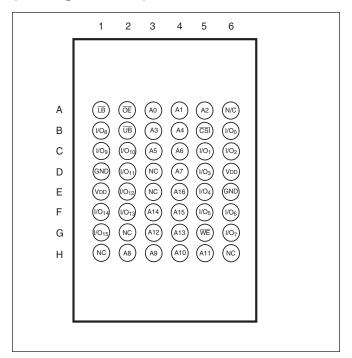
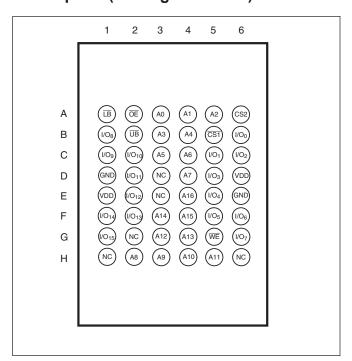


PIN CONFIGURATIONS

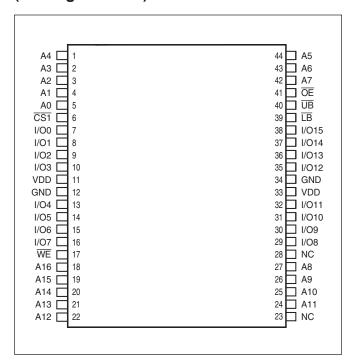
48-Pin mini BGA (6mm x 8mm) (Package Code B)



48-Pin mini BGA (6mm x 8mm) 2 CS Option (Package Code B2)



44-Pin mini TSOP (Type II) (Package Code T)



PIN DESCRIPTIONS

A0-A16	Address Inputs
I/O0-I/O15	Data Inputs/Outputs
CS1, CS2	Chip Enable Input
ŌĒ	Output Enable Input
WE	Write Enable Input
ĪB	Lower-byte Control (I/O0-I/O7)
ŪB	Upper-byte Control (I/O8-I/O15)
NC	No Connection
VDD	Power
GND	Ground

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TRUTH TABLE

							I/O PIN			
Mode	WE	CS1	CS2	ŌĒ	LΒ	ŪB	1/00-1/07	I/O8-I/O15	V _{DD} Current	
Not Selected	Х	Н	Х	Х	Х	Х	High-Z	High-Z	Isb1, Isb2	
	X	Χ	L	Χ	X	Χ	High-Z	High-Z	Isb1, Isb2	
	X	X	X	Χ	Н	Н	High-Z	High-Z	Isb1, Isb2	
Output Disabled	Н	L	Н	Н	L	Χ	High-Z	High-Z	Icc	
	Н	L	Н	Н	Χ	L	High-Z	High-Z	Icc	
Read	Н	L	Н	L	L	Н	D out	High-Z	Icc	
	Н	L	Н	L	Н	L	High-Z	Dout		
	Н	L	Н	L	L	L	Dout	Dout		
Write	L	L	Н	Х	L	Н	Din	High-Z	Icc	
	L	L	Н	Χ	Н	L	High-Z	Din		
	L	L	Н	Χ	L	L	DIN	Din		

ABSOLUTE MAXIMUM RATINGS(1)

Symbol	Parameter	Value	Unit
VTERM	Terminal Voltage with Respect to GND	-0.2 to V _{DD} +0.3	V
Тѕтс	Storage Temperature	-65 to +150	°C
Рт	Power Dissipation	1.0	W

Note:

OPERATING RANGE (VDD)

Range Ambient Temperature		IS62WV12816ALL	IS62WV12816BLL
Commercial	0°C to +70°C	1.65V - 2.2V	2.5V - 3.6V
Industrial	–40°C to +85°C	1.65V - 2.2V	2.5V - 3.6V

Stress greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the
device. This is a stress rating only and functional operation of the device at these or any other conditions above
those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating
conditions for extended periods may affect reliability.



DC ELECTRICAL CHARACTERISTICS (Over Operating Range)

Symbol	Parameter	Test Conditions	V DD	Min.	Max.	Unit
Vон	Output HIGH Voltage	Iон = -0.1 mA	1.65-2.2V	1.4	_	V
		IOH = -1 mA	2.5-3.6V	2.2	_	V
Vol	Output LOW Voltage	IoL = 0.1 mA	1.65-2.2V	_	0.2	V
		IoL = 2.1 mA	2.5-3.6V	_	0.4	V
VIH	Input HIGH Voltage		1.65-2.2V	1.4	V _{DD} + 0.2	V
			2.5-3.6V	2.2	$V_{DD} + 0.3$	V
VIL ⁽¹⁾	Input LOW Voltage		1.65-2.2V	-0.2	0.4	V
			2.5-3.6V	-0.2	0.8	V
ILI	Input Leakage	$GND \leq Vin \leq Vdd$		– 1	1	μΑ
ILO	Output Leakage	$GND \le Vout \le Vod, C$	Outputs Disabled	– 1	1	μΑ

Notes:

CAPACITANCE(1)

Symbol	Parameter	Conditions	Max.	Unit
Cin	Input Capacitance	V _{IN} = 0V	8	pF
Соит	Input/Output Capacitance	Vout = 0V	10	pF

^{1.} V_{IL} (min.) = -1.0V for pulse width less than 10 ns.

^{1.} Tested initially and after any design or process changes that may affect these parameters.



IS62WV12816ALL, POWER SUPPLY CHARACTERISTICS⁽¹⁾ (Over Operating Range)

Symbol	Parameter	Test Conditions	Max. 70	Unit
Icc	VDD Dynamic Operating	V _{DD} = Max., Com.	15	mA
	Supply Current	IOUT = 0 mA, f = fMAX Ind.	20	
Icc1	Operating Supply	V _{DD} = Max., Com.	3	mA
	Current	IOUT = 0 mA, f = 0 Ind.	3	
Is _B 1	TTL Standby Current	V _{DD} = Max., Com.	0.3	mA
	(TTL Inputs)	$V_{IN} = V_{IH} \text{ or } V_{IL}$ Ind. $\overline{CS1} = V_{IH}$, $CS2 = V_{IL}$,	0.3	
		f = 1 MHz OR		
	ULB Control	V_{DD} = Max., V_{IN} = V_{IH} or V_{IL} $\overline{CS1}$ = V_{IL} , f = 0, \overline{UB} = V_{IH} , \overline{LB} = V_{IH}		
IsB2	CMOS Standby	V _{DD} = Max., Com.	5	μA
	Current (CMOS Inputs)	$\overline{\text{CS1}} \ge \text{VDD} - 0.2\text{V}$, Ind. $\text{CS2} \le 0.2\text{V}$, $\text{VIN} \ge \text{VDD} - 0.2\text{V}$, or	10	·
		$VIN \leq VDD$ 0.2V, of OR		
	ULB Control	V_{DD} = Max., $\overline{CS1}$ = V _{IL} , CS2=V _{IH} V _{IN} \leq 0.2V, f = 0; \overline{UB} / \overline{LB} = V _{DD} $-$ 0.2V		

IS62WV12816BLL, POWER SUPPLY CHARACTERISTICS⁽¹⁾ (Over Operating Range)

Symbol	Parameter	Test Conditions	ı	/lax. 45	Max. 55	Unit
Icc	VDD Dynamic Operating	V _{DD} = Max., Co	om.	35	25	mA
	Supply Current	$IOUT = 0 \text{ mA}, f = f_{MAX}$	Ind.	40	30	
		ty	p. ⁽²⁾	25	20	
Icc1	Operating Supply	V _{DD} = Max., Co	om.	3	3	mA
	Current	$I_{OUT} = 0 \text{ mA}, f = 0$	Ind.	3	3	
Is _B 1	TTL Standby Current	V _{DD} = Max., Co	om.	0.3	0.3	mA
	(TTL Inputs)	VIN = VIH or VIL	Ind.	0.3	0.3	
		$\overline{\text{CS1}}$ = ViH, CS2 = ViL,				
		f = 1 MHz	OR			
	ULB Control	$\frac{V_{DD}}{CS1} = Max.$, $V_{IN} = V_{IH}$ or $\frac{V_{ID}}{CS1} = V_{IL}$, $f = 0$, $\overline{UB} = V_{IL}$				
IsB2	CMOS Standby	V _{DD} = Max., Co	om.	10	10	μA
	Current (CMOS Inputs)	$\overline{\text{CS1}} \ge \text{Vdd} - 0.2\text{V},$	Ind.	10	10	•
	, , ,	$CS2 \le 0.2V$, ty	p. ⁽²⁾	3	3	
		$Vin \ge Vdd - 0.2V$, or				
		$V_{IN} \le 0.2V, f = 0$	OR			
Nata	ULB Control	V_{DD} = Max., $\overline{CS1}$ = V_{IN} $V_{IN} \le 0.2V$, f = 0; \overline{UB} / \overline{LE}	•			

Note:

1. At f = fmax, address and data inputs are cycling at the maximum frequency, f = 0 means no input lines change.

2. Typical values are measured at V_{DD} = 3.0V, T_A = 25°C and not 100% tested.



AC TEST CONDITIONS

Parameter	62WV12816ALL (Unit)	62WV12816BLL (Unit)	
Input Pulse Level	0.4V to V _{DD} -0.2V	0.4V to VDD-0.3V	
Input Rise and Fall Times	5 ns	5ns	
Input and Output Timing and Reference Level	Vref	Vref	
Output Load	See Figures 1 and 2	See Figures 1 and 2	

	1.65-2.2V	2.5V - 3.6V
R1(Ω)	3070	3070
R2(Ω)	3150	3150
VREF	0.9V	1.5V
Vтм	1.8V	2.8V

AC TEST LOADS

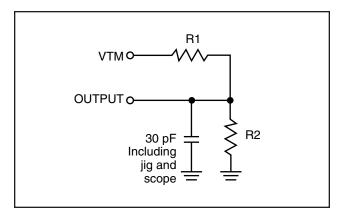


Figure 1

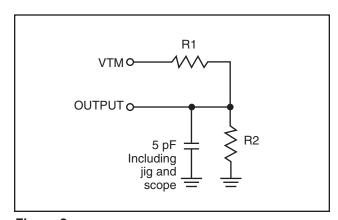


Figure 2



READ CYCLE SWITCHING CHARACTERISTICS⁽¹⁾ (Over Operating Range)

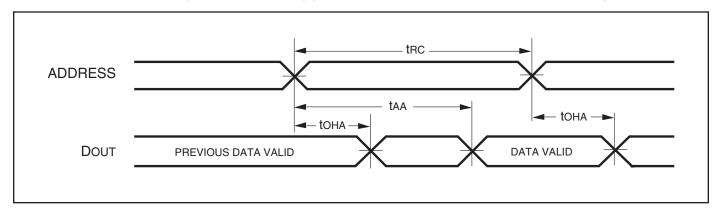
		45 ו	ıs	55 r	ns	70 ns		
Symbol	Parameter	Min.	Max.	Min.	Max.	Min.	Max.	Unit
t RC	Read Cycle Time	45	_	55	_	70	_	ns
t AA	Address Access Time	_	45	_	55	_	70	ns
t она	Output Hold Time	10	_	10	_	10	_	ns
tacs1/tacs2	CS1/CS2 Access Time	_	45	_	55	_	70	ns
t DOE	OE Access Time	_	20	_	25	_	35	ns
t HZOE ⁽²⁾	OE to High-Z Output	_	15	_	20	_	25	ns
tLZOE ⁽²⁾	OE to Low-Z Output	5	_	5	_	5	_	ns
thzcs1/thzcs2 ⁽²⁾	CS1/CS2 to High-Z Output	0	15	0	20	0	25	ns
tLZCS1/tLZCS2 ⁽²⁾	CS1/CS2 to Low-Z Output	10	_	10	_	10	_	ns
t BA	LB, UB Access Time	_	45	_	55	_	70	ns
t HZB	LB, UB to High-Z Output	0	15	0	20	0	25	ns
t LZB	LB, UB to Low-Z Output	0	_	0	_	0	_	ns

^{1.} Test conditions assume signal transition times of 5 ns or less, timing reference levels of 0.9V, input pulse levels of 0.4 to 1.4V and output loading specified in Figure 1.

2. Tested with the load in Figure 2. Transition is measured ±500 mV from steady-state voltage. Not 100% tested.

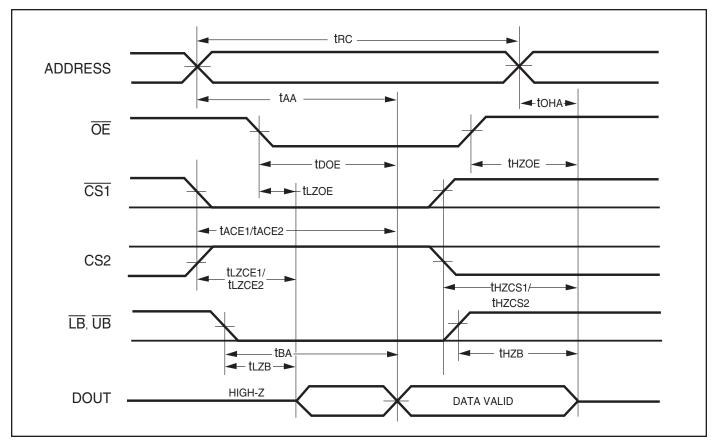


READ CYCLE NO. $1^{(1,2)}$ (Address Controlled) ($\overline{CS1} = \overline{OE} = V_{IL}$, $CS2 = \overline{WE} = V_{IH}$, \overline{UB} or $\overline{LB} = V_{IL}$)



AC WAVEFORMS

READ CYCLE NO. 2^(1,3) (CS1, CS2, OE, AND UB/LB Controlled)



- 1. $\overline{\text{WE}}$ is HIGH for a Read Cycle.
- 2. The device is continuously selected. \overline{OE} , $\overline{CS1}$, \overline{UB} , or \overline{LB} = V_{IL}. $CS2=\overline{WE}=V_{IH}$.
- 3. Address is valid prior to or coincident with CS1 LOW transition.



WRITE CYCLE SWITCHING CHARACTERISTICS(1,2) (Over Operating Range)

		45ns		55	55 ns 70 ns		ns	
Symbol	Parameter	Min.	Max.	Min.	Max.	Min.	Max.	Unit
twc	Write Cycle Time	45	_	55	_	70	_	ns
tscs1/tscs	2 CS1/CS2 to Write End	35	_	45	_	60	_	ns
taw	Address Setup Time to Write End	35	_	45	_	60	_	ns
t HA	Address Hold from Write End	0	_	0	_	0	_	ns
t sa	Address Setup Time	0	_	0	_	0	_	ns
t PWB	LB, UB Valid to End of Write	35	_	45	_	60	_	ns
t PWE	WE Pulse Width	35	_	40	_	50	_	ns
tsp	Data Setup to Write End	20	_	25	_	30	_	ns
t HD	Data Hold from Write End	0	_	0	_	0	_	ns
thzwe ⁽³⁾	WE LOW to High-Z Output	_	20	_	20	_	20	ns
tLZWE ⁽³⁾	WE HIGH to Low-Z Output	5	_	5	_	5	_	ns

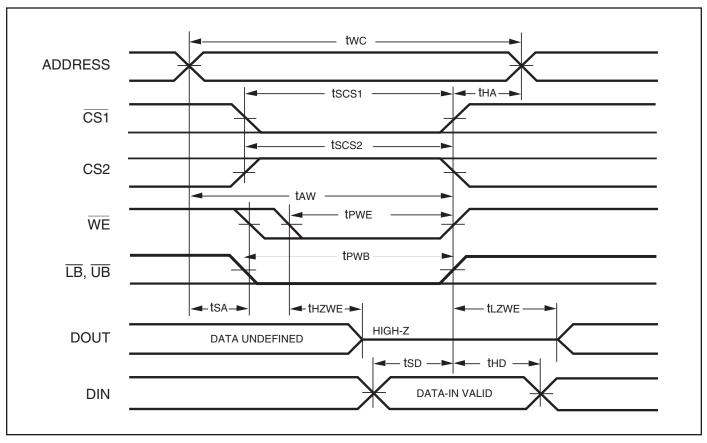
^{1.} Test conditions assume signal transition times of 5 ns or less, timing reference levels of 0.9V, input pulse levels of 0.4V to 1.4V and output loading specified in Figure 1.

^{2.} The internal write time is defined by the overlap of $\overline{\text{CS1}}$ LOW, CS2 HIGH and $\overline{\text{UB}}$ or $\overline{\text{LB}}$, and $\overline{\text{WE}}$ LOW. All signals must be in valid states to initiate a Write, but any one can go inactive to terminate the Write. The Data Input Setup and Hold timing are referenced to the rising or falling edge of the signal that terminates the write.

^{3.} Tested with the load in Figure 2. Transition is measured ±500 mV from steady-state voltage. Not 100% tested.



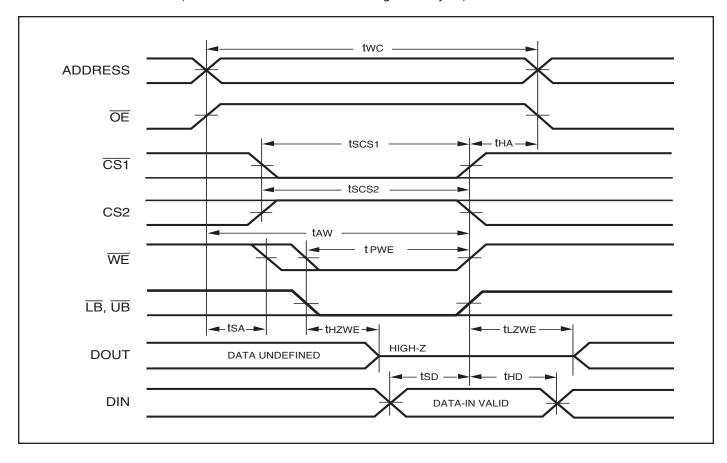
WRITE CYCLE NO. $1^{(1,2)}$ ($\overline{CS1}$ Controlled, \overline{OE} = HIGH or LOW)



- 1. WRITE is an internally generated signal asserted during an overlap of the LOW states on the $\overline{\text{CS1}}$, CS2 and $\overline{\text{WE}}$ inputs and at least one of the \overline{LB} and \overline{UB} inputs being in the LOW state. 2. WRITE = $(\overline{CS1})[(\overline{LB}) = (\overline{UB})](\overline{WE})$.

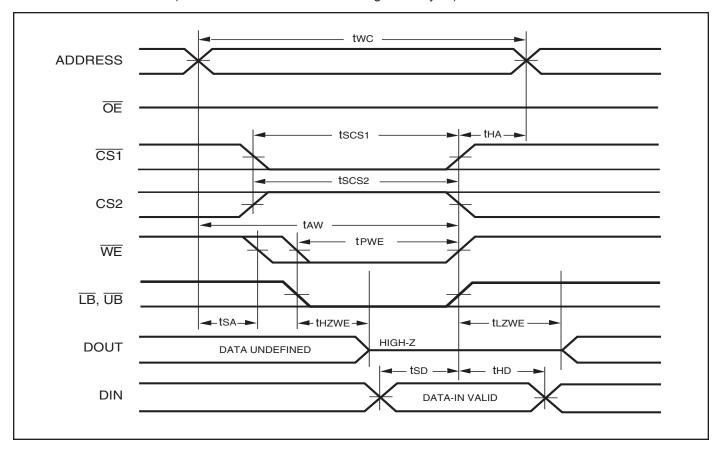


WRITE CYCLE NO. 2 (WE Controlled: OE is HIGH During Write Cycle)



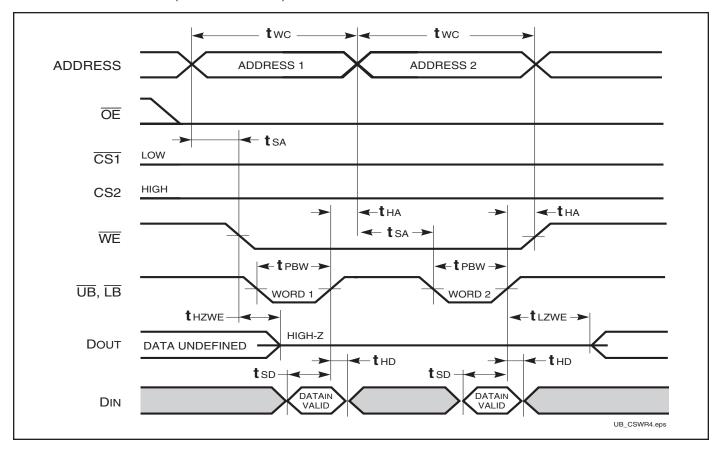


WRITE CYCLE NO. 3 (WE Controlled: OE is LOW During Write Cycle)





WRITE CYCLE NO. 4 (UB/LB Controlled)

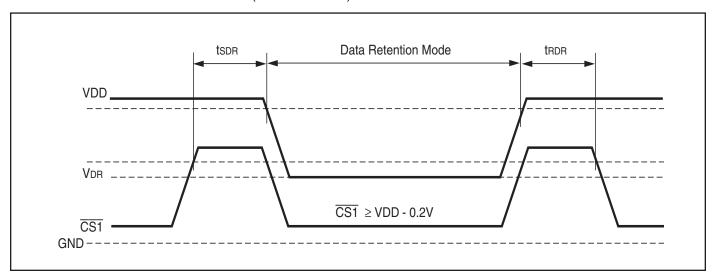




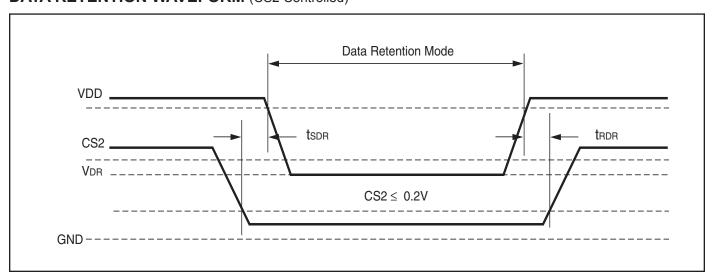
DATA RETENTION SWITCHING CHARACTERISTICS

Symbol	Parameter	Test Condition	Min.	Max.	Unit	
VdR	VDD for Data Retention	See Data Retention Waveform	1.0	3.6	V	
IDR	Data Retention Current	$V_{DD} = 1.0V, \overline{CS1} \ge V_{DD} - 0.2V$	_	10	μΑ	
tsdr	Data Retention Setup Time	See Data Retention Waveform	0	_	ns	
trdr	Recovery Time	See Data Retention Waveform	trc	_	ns	

DATA RETENTION WAVEFORM (CS1 Controlled)



DATA RETENTION WAVEFORM (CS2 Controlled)





ORDERING INFORMATION: IS62WV12816ALL (1.65V - 2.2V)

Commercial Range: 0°C to +70°C

	Speed (ns)	Order Part No.	Package
Ī	70	IS62WV12816ALL-70T	TSOP (Type II)

Industrial Range: -40°C to +85°C

Speed (ns)	Order Part No.	Package
70	IS62WV12816ALL-70TI	TSOP (Type II)
70	IS62WV12816ALL-70BI	mini BGA (6mm x 8mm)
70	IS62WV12816ALL-70BLI	mini BGA (6mm x 8mm), Lead-free
70	IS62WV12816ALL-70B2I	mini BGA (6mm x 8mm), 2 CS Option

ORDERING INFORMATION: IS62WV12816BLL (2.5V - 3.6V)

Commercial Range: 0°C to +70°C

Speed (ns)	Order Part No.	Package
45	IS62WV12816BLL-45B	mini BGA (6mm x 8mm)
45	IS62WV12816BLL-45B2	mini BGA (6mm x 8mm), 2 CS Option
55	IS62WV12816BLL-55T	TSOP (Type II)

Industrial Range: -40°C to +85°C

Speed (ns)	Order Part No.	Package
45	IS62WV12816BLL-45TLI	TSOP (Type II), Lead-free
45	IS62WV12816BLL-45BLI	mini BGA (6mm x 8mm), Lead-free
55	IS62WV12816BLL-55TI	TSOP (Type II)
55	IS62WV12816BLL-55TLI	TSOP (Type II), Lead-free
55	IS62WV12816BLL-55BI	mini BGA (6mm x 8mm)
55	IS62WV12816BLL-55BLI	mini BGA (6mm x 8mm), Lead-free
55	IS62WV12816BLL-55B2I	mini BGA (6mm x 8mm), 2 CS Option
55	IS62WV12816BLL-55B2L	I mini BGA (6mm x 8mm), 2 CS Option, Lead-free



